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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Jan Harries HANSEN et al.

International Application No.: PCT/DK03/00222

International Filing Date: 2 April 2003

Priority Date Claimed:

15 April 2002

For:

METHOD AND APPARATUS FOR MEASURING LIGHT

REFLECTIONS OF AN OBJECT

## PRELIMINARY AMENDMENT

Commissioner for Patents P.O. Box 1450 Arlington, VA 22313-1450 Attn: DO/EO/US

SIR:

Prior to examination of the captioned above application, kindly amend the application as follows: